

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 59349.00031	SERIAL NO. 10/540,470
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT Naohide OGAWA, et al.	
		FILING DATE June 23, 2005	GROUP

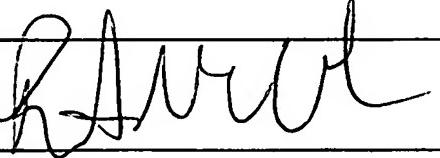
U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO PART.
RW	AG	2001-150374	June 5, 2001	JAPAN			X
RW	AH	11-048170	February 23, 1999	JAPAN			X
RW	AI	2002-144260	May 21, 2002	JAPAN			X
RW	AJ	06-114766	April 26, 1994	JAPAN			X
	AK						

OTHER REFERENCES *(Including Author, Title, Date, Pertinent Pages, Etc.)*

	AL			
	AM			
	AN			
EXAMINER		DATE CONSIDERED	<i>3/12/07</i>	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 59349.00031	10/540470 New Application
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT OGAWA et al	
		FILING DATE June 23, 2005	GROUP Not yet assigned

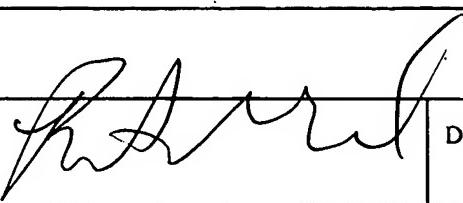
U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
EW	AA	6,064,167	05/16/00	Takenaka et al			
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO PART.
	AG	JP 2002-144260	05/21/02	Japan			
	AH	EP 1103449-A1	05/30/01	European			
	AI	JP 7-334227-A	12/22/95	Japan			
	AJ	JP 2003-227464	10/09/01	Japan			
	AK						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AL	
	AM	
	AN	
EXAMINER		DATE CONSIDERED 3/12/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.